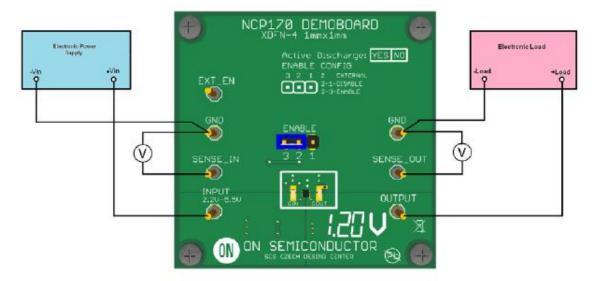
ON Semiconductor®



Test Procedure for the NCP170AMX250GEVB Evaluation Board



Test procedure:

1. Check the position of jumper and correct this if necesary in acordance with the picture above.

- 2. Connect the test setup as shown Figure above
- 3. Appy an input voltage Vin = 3.5 V
- 4. Appy Iout = 0mA load.
- 5. Check that Vout is **2.5 V** +/-1%.
- 6. Increase lout up to 0.15 A
- 7. Check that Vout is **2.5 V** +/-1%.
- 7. Increase Vin up to **5.5 V** and decrease the load in accordance with **SOA**
- 8. Power down the Load
- 9. Power down the Vcc
- 10. End of test